

DS55451/2/3/4, DS75451/2/3/4 Series Dual Peripheral Drivers

General Description

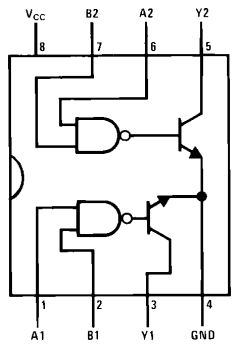
The DS7545X series of dual peripheral drivers is a family of versatile devices designed for use in systems that use TTL logic. Typical applications include high speed logic buffers, power drivers, relay drivers, lamp drivers, MOS drivers, bus drivers and memory drivers.

The DS55451/DS75451, DS55452/DS75452, DS55453/DS75453 and DS55454/DS75454 are dual peripheral AND, NAND, OR and NOR drivers, respectively, (positive logic) with the output of the logic gates internally connected to the bases of the NPN output transistors.

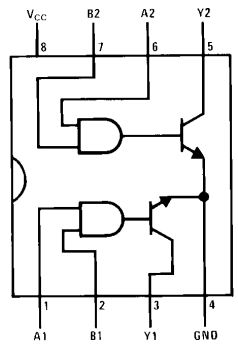
Features

- 300 mA output current capability
- High voltage outputs
- No output latch-up at 20V
- High speed switching
- Choice of logic function
- TTL compatible diode-clamped inputs
- Standard supply voltages
- Replaces TI "A" and "B" series

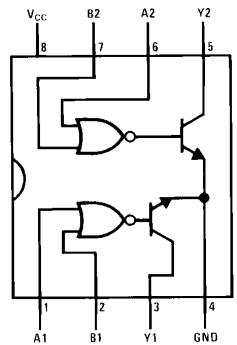
Connection Diagrams (Dual-In-Line and Metal Can Packages)



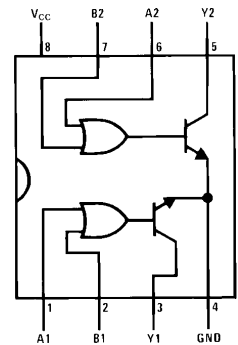
TL/F/5824-2

Top View
**Order Number DS55451J-8,
DS75451M or DS75451N**


TL/F/5824-3

Top View
**Order Number DS55452J-8,
DS75452M or DS75452N**


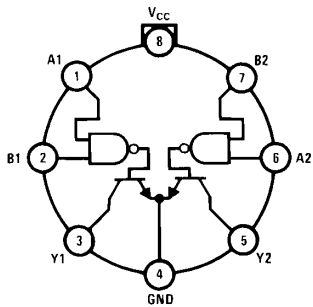
TL/F/5824-4

Top View
**Order Number DS55453J-8,
DS75453M or DS75453N**


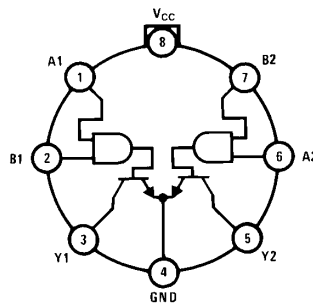
TL/F/5824-5

Top View
**Order Number DS55454J-8,
DS75454M or DS75454N**
See NS Package Numbers J08A, M08A* or N08E

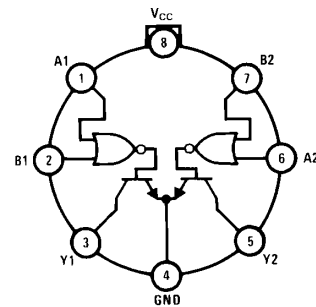
*See Note 5 and Appendix E regarding S.O. package power dissipation constraints.



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Top View
Order Number DS55451H


TL/F/5824-7

Top View
Order Number DS55452H
See NS Package Number H08C


TL/F/5824-8

Top View
Order Number DS55453H

(Pin 4 is in Electrical Contact with the Case)

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

| | |
|--|---------|
| Supply Voltage, (V_{CC}) (Note 2) | 7.0V |
| Input Voltage | 5.5V |
| Inter-Emitter Voltage (Note 3) | 5.5V |
| Output Voltage (Note 4) | 30V |
| DS55451/DS75451, DS55452/DS75452, DS55453/DS75453, DS55454/DS75454 | |
| Output Current (Note 5) | 300 mA |
| DS55451/DS75451, DS55452/DS75452, DS55453/DS75453, DS55454/DS75454 | |
| DS75451/2/3/4 Maximum Power (Note 5) | |
| Dissipation [†] at 25°C | |
| Cavity Package | 1090 mW |
| Molded DIP Package | 957 mW |
| TO-5 Package | 760 mW |
| SO Package | 632 mW |

| | |
|--------------------------------------|-----------------|
| Storage Temperature Range | -65°C to +150°C |
| Lead Temperature (Soldering, 4 sec.) | 260°C |

Operating Conditions

| | Min | Max | Units |
|------------------------------|------|------|-------|
| Supply Voltage, (V_{CC}) | | | |
| DS5545X | 4.5 | 5.5 | V |
| DS7545X | 4.75 | 5.25 | V |
| Temperature, (T_A) | | | |
| DS5545X | -55 | +125 | °C |
| DS7545X | 0 | +70 | °C |

[†] Derate cavity package 7.3 mW/°C above 25°C; derate molded package 7.7 mW/°C above 25°C; derate TO-5 package 5.1 mW/°C above 25°C; derate SO package 7.56 mW/°C above 25°C.

Electrical Characteristics

DS55451/DS75451, DS55452/DS75452, DS55453/DS75453, DS55454/DS75454 (Notes 6 and 7)

| Symbol | Parameter | Conditions | | Min | Typ | Max | Units | |
|---------------------------|--|--|--------------------------|---------------------------|------------------|------|---------------|---------------|
| V_{IH} | High-Level Input Voltage | (Figure 7) | | 2 | | | V | |
| V_{IL} | Low-Level Input Voltage | | | | | 0.8 | V | |
| V_I | Input Clamp Voltage | $V_{CC} = \text{Min}, I_I = -12 \text{ mA}$ | | | | -1.5 | V | |
| V_{OL} | Low-Level Output Voltage | $V_{CC} = \text{Min},$ (Figure 7) | $V_{IL} = 0.8 \text{ V}$ | $I_{OL} = 100 \text{ mA}$ | DS55451, DS55453 | 0.25 | 0.5 | V |
| | | | | | DS75451, DS75453 | 0.25 | 0.4 | V |
| | | | | $I_{OL} = 300 \text{ mA}$ | DS55451, DS55453 | 0.5 | 0.8 | V |
| | | | | DS75451, DS75453 | 0.5 | 0.7 | V | |
| | | | $V_{IH} = 2 \text{ V}$ | $I_{OL} = 100 \text{ mA}$ | DS55452, DS55454 | 0.25 | 0.5 | V |
| | | | | | DS75452, DS75454 | 0.25 | 0.4 | V |
| $I_{OL} = 300 \text{ mA}$ | DS55452, DS55454 | 0.5 | | 0.8 | V | | | |
| | | DS75452, DS75454 | 0.5 | 0.7 | V | | | |
| I_{OH} | High-Level Output Current | $V_{CC} = \text{Min},$ (Figure 7) | $V_{OH} = 30 \text{ V}$ | $V_{IH} = 2 \text{ V}$ | DS55451, DS55453 | | 300 | μA |
| | | | | | DS75451, DS75453 | | 100 | μA |
| | | | | $V_{IL} = 0.8 \text{ V}$ | DS55452, DS55454 | | 300 | μA |
| | | | | | DS75452, DS75454 | | 100 | μA |
| I_I | Input Current at Maximum Input Voltage | $V_{CC} = \text{Max}, V_I = 5.5 \text{ V},$ (Figure 9) | | | | 1 | mA | |
| I_{IH} | High-Level Input Current | $V_{CC} = \text{Max}, V_I = 2.4 \text{ V},$ (Figure 9) | | | | 40 | μA | |
| I_{IL} | Low-Level Input Current | $V_{CC} = \text{Max}, V_I = 0.4 \text{ V},$ (Figure 8) | | | -1 | -1.6 | mA | |
| I_{CCH} | Supply Current, Outputs High | $V_{CC} = \text{Max},$ (Figure 10) | $V_I = 5 \text{ V}$ | DS55451/DS75451 | 7 | 11 | mA | |
| | | | $V_I = 0 \text{ V}$ | DS55452/DS75452 | 11 | 14 | mA | |
| | | | $V_I = 5 \text{ V}$ | DS55453/DS75453 | 8 | 11 | mA | |
| | | | $V_I = 0 \text{ V}$ | DS55454/DS75454 | 13 | 17 | mA | |
| I_{CCL} | Supply Current, Outputs Low | $V_{CC} = \text{Max},$ (Figure 10) | $V_I = 0 \text{ V}$ | DS55451/DS75451 | 52 | 65 | mA | |
| | | | $V_I = 5 \text{ V}$ | DS55452/DS75452 | 56 | 71 | mA | |
| | | | $V_I = 0 \text{ V}$ | DS55453/DS75453 | 54 | 68 | mA | |
| | | | $V_I = 5 \text{ V}$ | DS55454/DS75454 | 61 | 79 | mA | |

Switching Characteristics

DS55451/DS75451, DS55452/DS75452, DS55453/DS75453, DS55454/DS75454 ($V_{CC} = 5V$, $T_A = 25^\circ C$)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------|--|---|-----------------|-----|-----|-------|
| t_{PLH} | Propagation Delay Time, Low-to-High Level Output | $C_L = 15 \text{ pF}$, $R_L = 50\Omega$, $I_O \approx 200 \text{ mA}$, (Figure 14) | DS55451/DS75451 | 18 | 25 | ns |
| | | | DS55452/DS75452 | 26 | 35 | ns |
| | | | DS55453/DS75453 | 18 | 25 | ns |
| | | | DS55454/DS75454 | 27 | 35 | ns |
| t_{PHL} | Propagation Delay Time, High-to-Low Level Output | $C_L = 15 \text{ pF}$, $R_L = 50\Omega$, $I_O \approx 200 \text{ mA}$, (Figure 14) | DS55451/DS75451 | 18 | 25 | ns |
| | | | DS55452/DS75452 | 24 | 35 | ns |
| | | | DS55453/DS75453 | 16 | 25 | ns |
| | | | DS55454/DS75454 | 24 | 35 | ns |
| t_{TLH} | Transition Time, Low-to-High Level Output | $C_L = 15 \text{ pF}$, $R_L = 50\Omega$, $I_O \approx 200\text{mA}$, (Figure 14) | | 5 | 8 | ns |
| t_{THL} | Transition Time, High-to-Low Level Output | $C_L = 15 \text{ pF}$, $R_L = 50\Omega$, $I_O \approx 200 \text{ mA}$, (Figure 14) | | 7 | 12 | ns |
| V_{OH} | High-Level Output Voltage after Switching | $V_S = 20V$, $I_O \approx 300 \text{ mA}$, (Figure 15) | $V_S - 6.5$ | | | mV |

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

Note 2: Voltage values are with respect to network ground terminal unless otherwise specified.

Note 3: The voltage between two emitters of a multiple-emitter transistor.

Note 4: The maximum voltage which should be applied to any output when it is in the "OFF" state.

Note 5: Both halves of these dual circuits may conduct rated current simultaneously; however, power dissipation averaged over a short time interval must fall within the continuous dissipation rating.

Note 6: Unless otherwise specified min/max limits apply across the $-55^\circ C$ to $+125^\circ C$ temperature range for the DS55450 series and across the $0^\circ C$ to $+70^\circ C$ range for the DS7545X series. All typicals are given for $V_{CC} = +5V$ and $T_A = 25^\circ C$.

Note 7: All currents into device pins shown as positive, out of device pins as negative, all voltages referenced to ground unless otherwise noted. All values shown as max or min on absolute value basis.

Truth Tables (H = high level, L = low level)

DS55451/DS75451

| A | B | Y |
|---|---|---------------|
| L | L | L (ON State) |
| L | H | L (ON State) |
| H | L | L (ON State) |
| H | H | H (OFF State) |

DS55452/DS75452

| A | B | Y |
|---|---|---------------|
| L | L | H (OFF State) |
| L | H | H (OFF State) |
| H | L | H (OFF State) |
| H | H | L (ON State) |

DS55453/DS75453

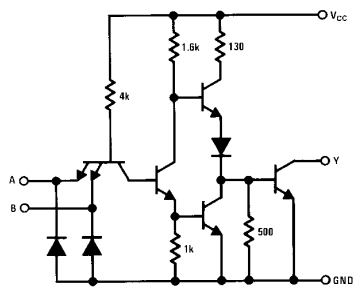
| A | B | Y |
|---|---|---------------|
| L | L | L (ON State) |
| L | H | H (OFF State) |
| H | L | H (OFF State) |
| H | H | H (OFF State) |

DS55454/DS75454

| A | B | Y |
|---|---|---------------|
| L | L | H (OFF State) |
| L | H | L (ON State) |
| H | L | L (ON State) |
| H | H | L (ON State) |

Schematic Diagrams

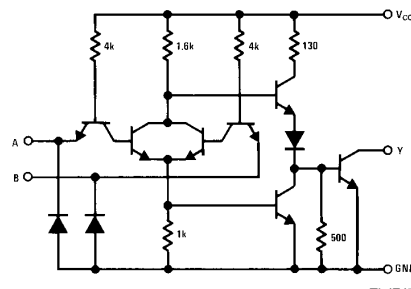
DS55451/DS75451



TL/F/5824-11

Resistor values shown are nominal.

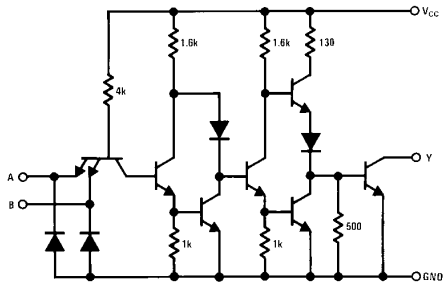
DS55453/DS75453



TL/F/5824-13

Resistor values shown are nominal.

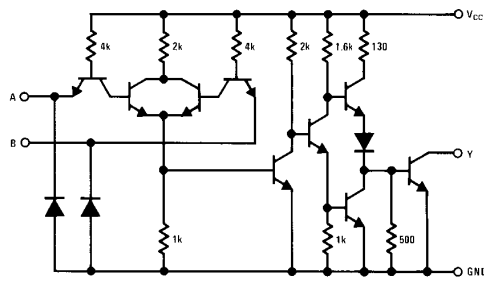
DS55452/DS75452



TL/F/5824-12

Resistor values shown are nominal.

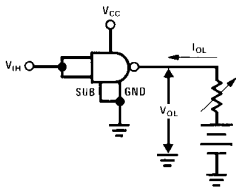
DS55454/DS75454



TL/F/5824-14

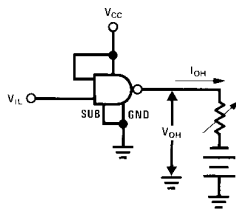
Resistor values shown are nominal.

DC Test Circuits



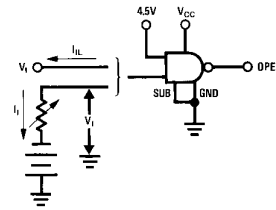
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Both inputs are tested simultaneously.
FIGURE 1. V_{IH} , V_{OL}



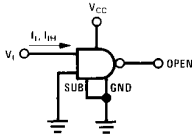
TL/F/5824-16

Each input is tested separately.
FIGURE 2. V_{IL} , V_{OH}



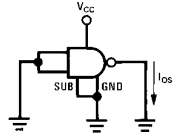
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Each input is tested separately.
FIGURE 3. V_I , I_{IL}



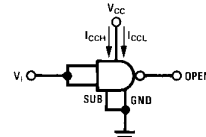
TL/F/5824-18

Each input is tested separately.
FIGURE 4. I_I , I_{IH}



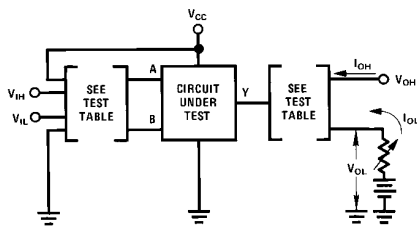
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Each input is tested separately.
FIGURE 5. I_{OS}



TL/F/5824-20

Both gates are tested simultaneously.
FIGURE 6. I_{CCH} , I_{CCL}



TL/F/5824-21

FIGURE 7. V_{IH} , V_{IL} , I_{OH} , V_{OL}

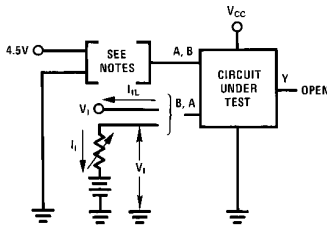
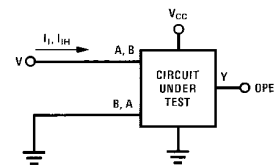


FIGURE 8. V_I , V_{IL}

Note A: Each input is tested separately.
Note B: When testing DS55453/DS75453, DS55454/DS75454, input not under test is grounded. For all other circuits it is at 4.5V.

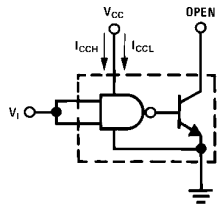
TL/F/5824-22



Each input is tested separately.

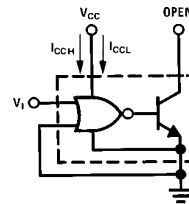
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FIGURE 9. I_I , I_{IH}



TL/F/5824-24

Both gates are tested simultaneously.
FIGURE 10. I_{CCH} , I_{CCL} for AND, NAND Circuits

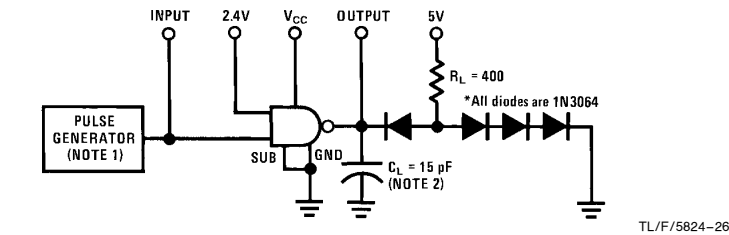


TL/F/5824-25

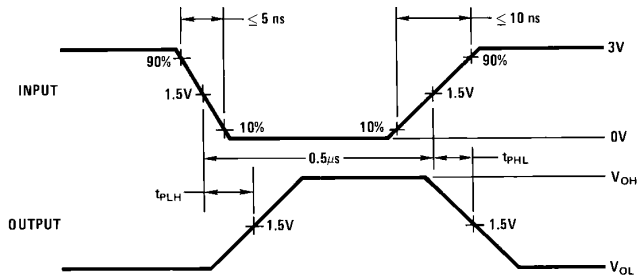
Both gates are tested simultaneously.
FIGURE 11. I_{CCH} , I_{CCL} for OR, NOR Circuits

| Circuit | Input Under Test | Other Input | Output | |
|---------|------------------|-------------|----------|----------|
| | | | Apply | Measure |
| DS55451 | V_{IH} | V_{IH} | V_{OH} | I_{OH} |
| | V_{IL} | V_{CC} | I_{OL} | V_{OL} |
| DS55452 | V_{IH} | V_{IH} | I_{OL} | V_{OL} |
| | V_{IL} | V_{CC} | V_{OH} | I_{OH} |
| DS55453 | V_{IH} | Gnd | V_{OH} | I_{OH} |
| | V_{IL} | V_{IL} | I_{OL} | V_{OH} |
| DS55454 | V_{IH} | Gnd | I_{OL} | V_{OL} |
| | V_{IL} | V_{IL} | V_{OH} | I_{OH} |

AC Test Circuits and Switching Time Waveforms



TL/F/5824-26

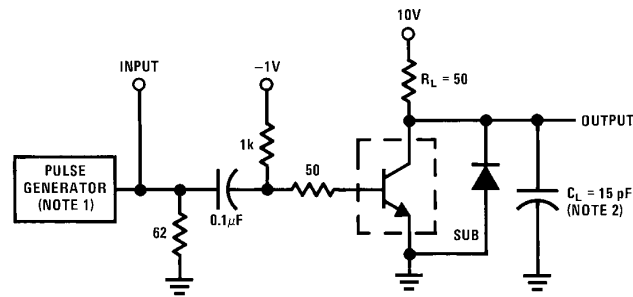


TL/F/5824-27

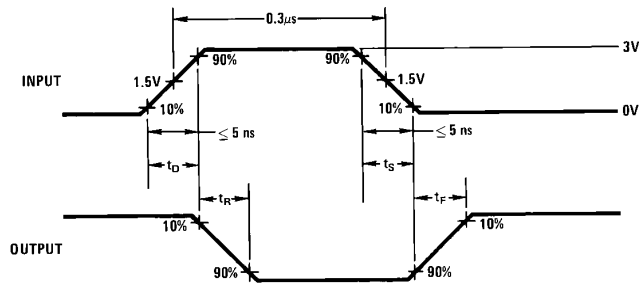
Note 1: The pulse generator has the following characteristics: PRR = 1 MHz, $Z_{OUT} \approx 50\Omega$.

Note 2: C_L includes probe and jig capacitance.

FIGURE 12. Propagation Delay Times, Each Gate



TL/F/5824-28



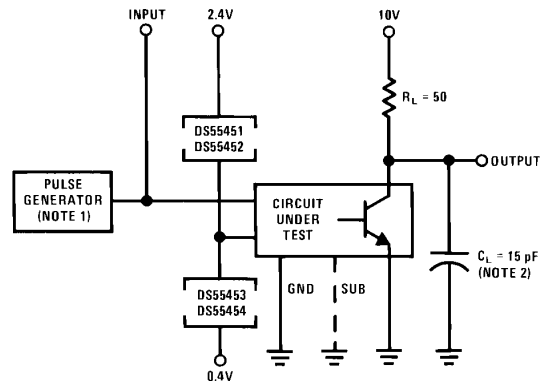
TL/F/5824-29

Note 1: The pulse generator has the following characteristics: duty cycle $\le 1\%$, $Z_{OUT} \approx 50\Omega$.

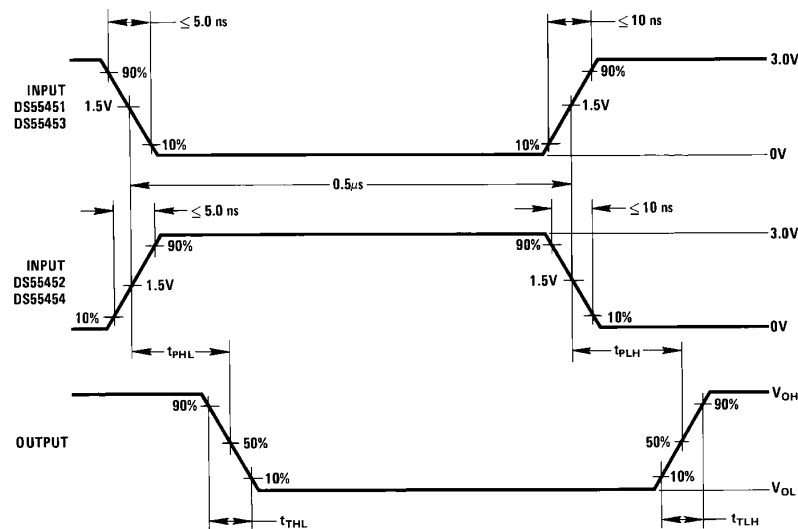
Note 2: C_L includes probe and jig capacitance.

FIGURE 13. Switching Times, Each Transistor

AC Test Circuits and Switching Time Waveforms (Continued)



TL/F/5824-30



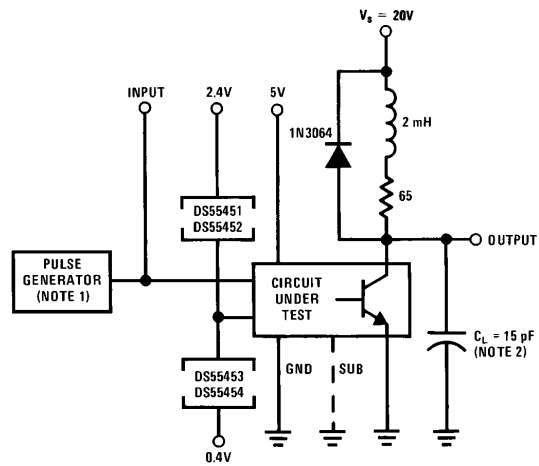
Note 1: The pulse generator has the following characteristics: PRR = 1.0 MHz, $Z_{OUT} \approx 50\ \Omega$.

Note 2: C_L includes probe and jig capacitance.

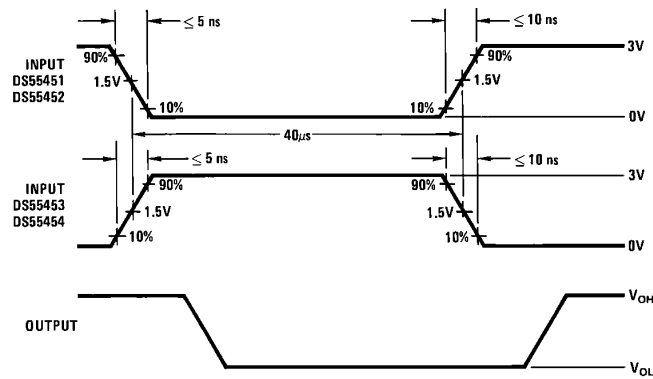
TL/F/5824-31

FIGURE 14. Switching Times of Complete Drivers

AC Test Circuits and Switching Time Waveforms (Continued)



TL/F/5824-32



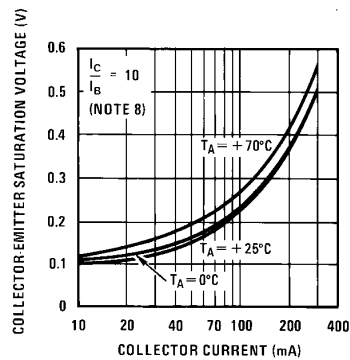
TL/F/5824-33

Note 1: The pulse generator has the following characteristics: PRR = 12.5 kHz, $Z_{OUT} \approx 50\Omega$.

Note 2: C_L includes probe and jig capacitance.

FIGURE 15. Latch-UP Test of Complete Drivers

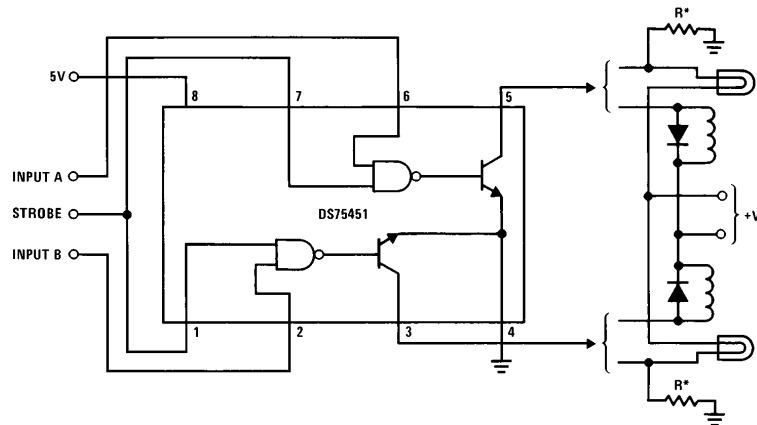
Typical Performance Characteristics



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FIGURE 16. Transistor Collector-Emitter Saturation Voltage vs Collector Current

Typical Applications



*Optional keep-alive resistors maintain off-state lamp current at $\approx 10\%$ to reduce surge current.

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FIGURE 17. Dual Lamp or Relay Driver

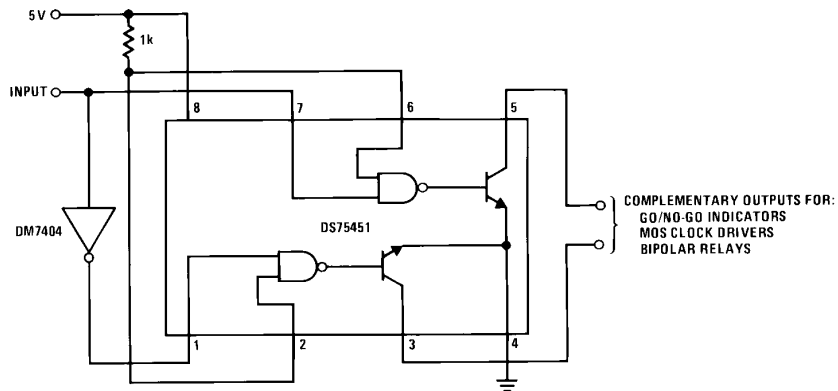


FIGURE 18. Complementary Driver

TL/F/5824-47

Typical Applications (Continued)

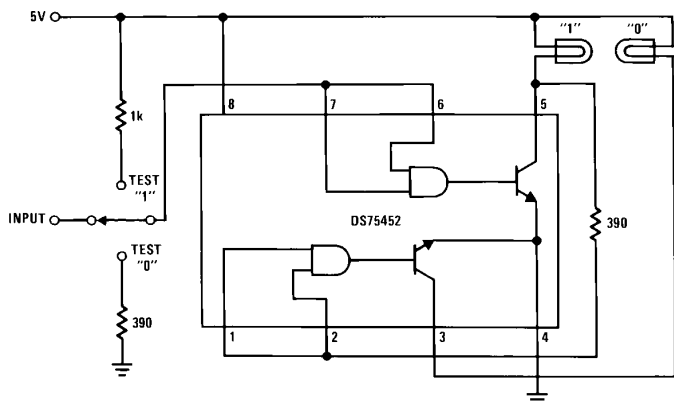
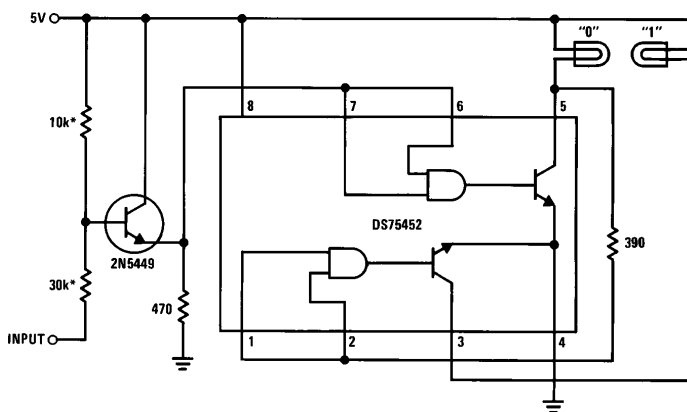


FIGURE 19. TTL or DTL Positive Logic-Level Detector

TL/F/5824-48



*The two input resistors must be adjusted for the level of MOS input.

FIGURE 20. MOS Negative Logic-Level Detector

TL/F/5824-49

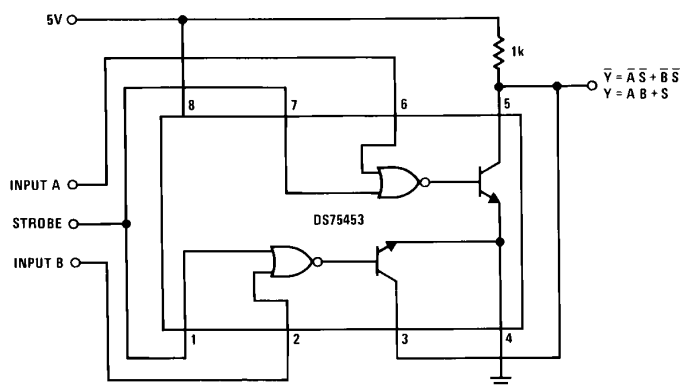
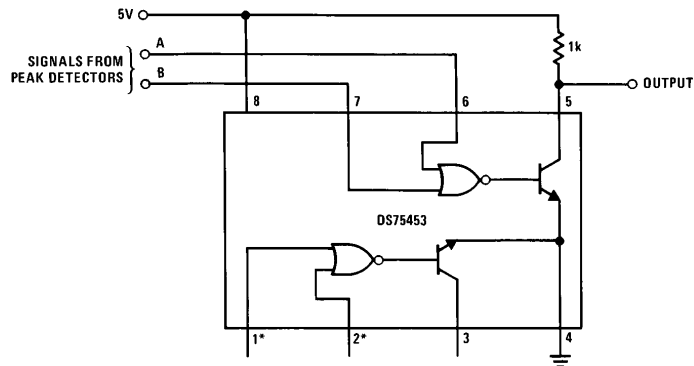


FIGURE 21. Logic Signal Comparator

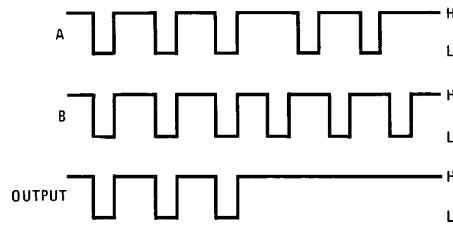
TL/F/5824-50

Typical Applications (Continued)



*If inputs are unused, they should be connected to +5V through a 1k resistor.

TL/F/5824-51



TL/F/5824-52

Low output occurs only when inputs are low simultaneously.

FIGURE 22. In-Phase Detector

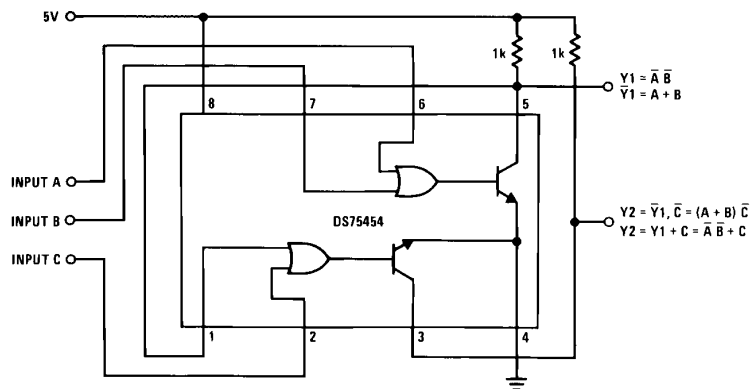


FIGURE 23. Multifunction Logic-Signal Comparator

TL/F/5824-53

Typical Applications (Continued)

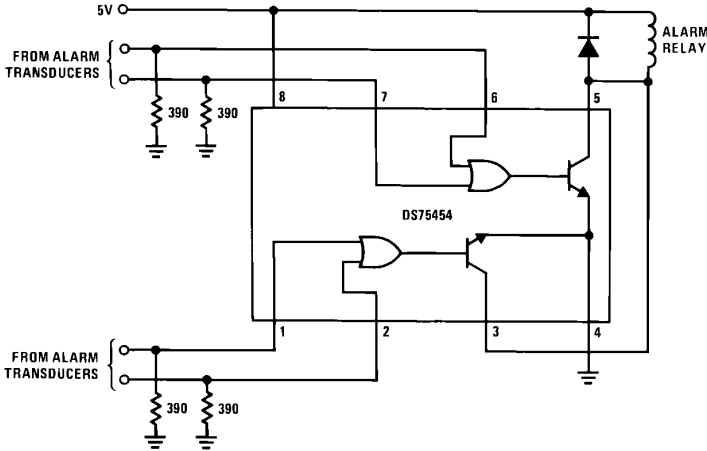
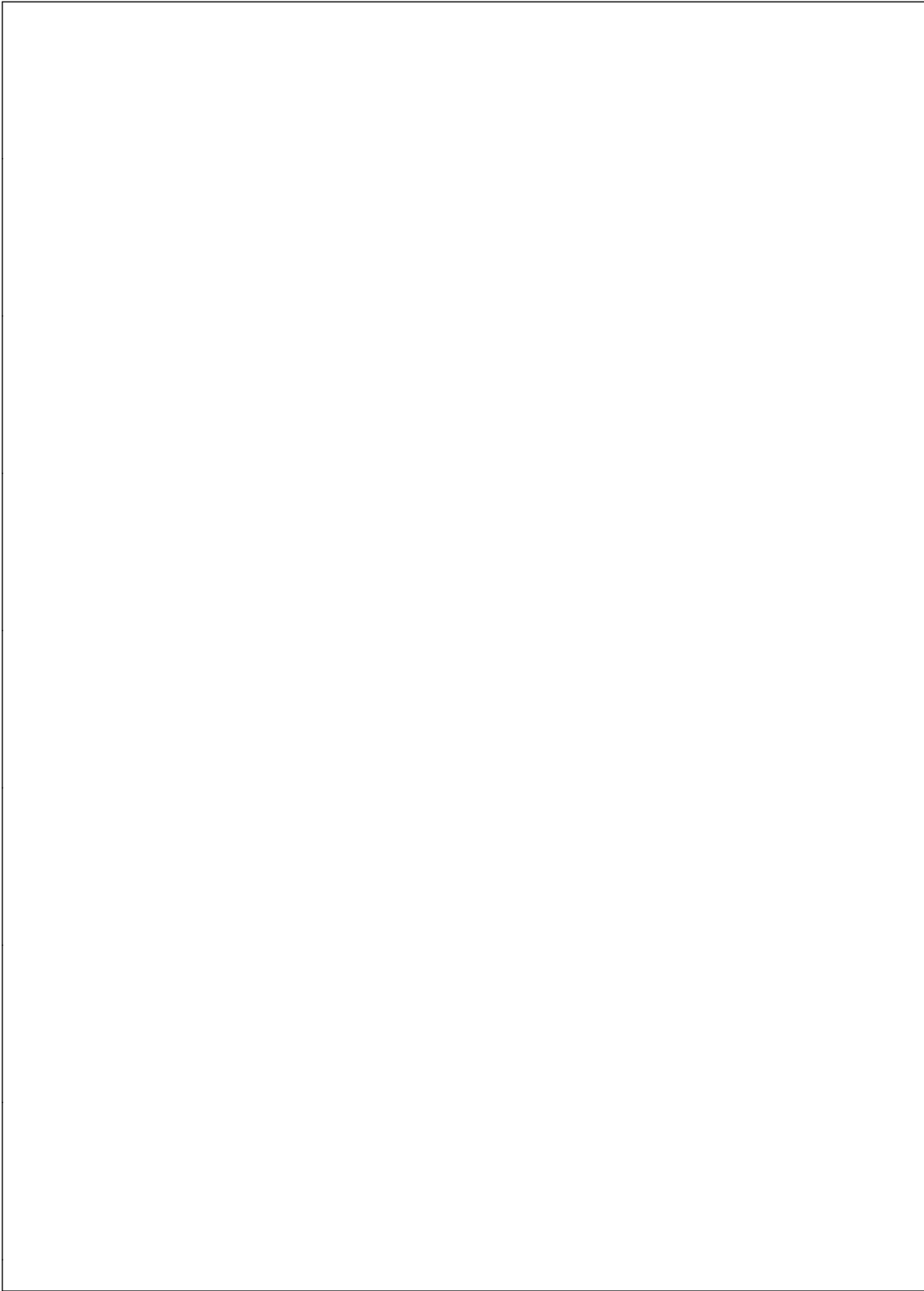
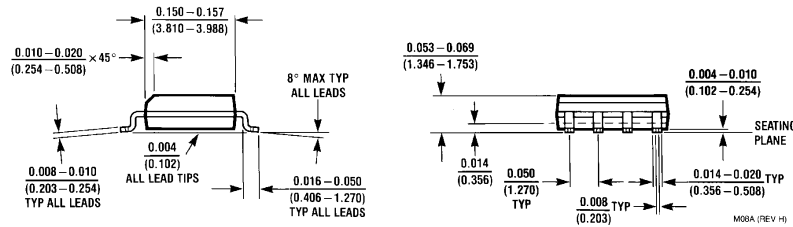
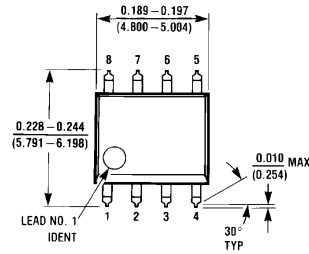


FIGURE 24. Alarm Detector

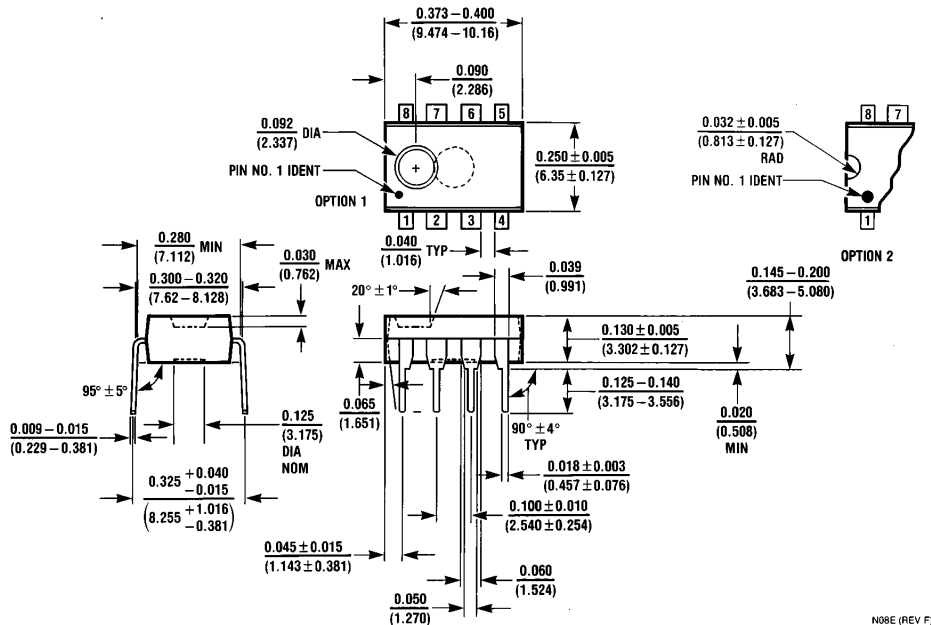
TL/F/5824-54



Physical Dimensions inches (millimeters) (Continued)



SO Package (M)
Order Number DS75451M, DS75452M, DS75453M or DS75454M
NS Package Number M08A



Molded Dual-In-Line Package (N)
Order Number DS75451N, DS75452N, DS75453N, DS75454N
NS Package Number N08E

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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